Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/053,079	FLEISCHER ET AL.
Examiner	Art Unit

Hanh Nguyen

2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	351	5/1/2007	HN		
	238				
	216				
	468				
	217				
,	220				
	237				
	242				
	395.21				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
370	351	5/1/2007	HN		
	468				
370	238				

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